



IECQ Certificate of Approval Independent Testing Laboratory

IECQ Certificate No.:	IECQ-L DEKRA 17.0001-01	Issue No.:	1	Status:	Current
Additional Site to Certification: IECQ-L DEKRA 17.0001		Originally Issued: 2011/11/27			
Supersedes:	IECQ-L NSAIUS 08.0006 Issue 6	Issue Date:	2017/11/27	Site Added:	2017/11/27
CB Reference No.:	DEKRA-C10B	Expiration:	2020/11/26		

Integrated Service Technology (Shenzhen) Co., Ltd.
 1F, Bldg Chungu, MeiShengChuangGu Tech Park, No68,
 No.10 Longchuang Road, Baoan,
 Shenzhen, Guangdong Province
 China

The organization, facilities and procedures have been assessed and found to comply with the applicable requirements for Independent Testing Laboratory organization approval, in support of the IECQ system, which is in accordance with the Basic Rules IECQ 01 and Rules of Procedure IECQ 03-6 "Independent Testing Laboratory Assessment Program Requirements" of the IEC Quality Assessment System for Electronic Components (IECQ) and applicable requirements of ISO/IEC 17025: 2005 for the testing of electronic components under the IECQ.

Scope:
Environmental and Reliability Testing of Electronic Components, Assemblies, and Related Materials
 -
See attached Schedule of Scope

-- Attached Schedule: IECQ-L DEKRA 17.0001-01-S Rev1.pdf --

Approved by Certification Body (CB): DEKRA Certification B.V.

Meander 1051
 Arnhem
 Netherlands

Authorized person:
Ted Gaertner



The validity of this certificate is maintained through on-going surveillance audits by the IECQ CB issuing this certificate.
 This Certificate of Conformity may be suspended or withdrawn in accordance with the Rules of Procedure of the IECQ System and its Schemes.
 This certificate and any schedule(s) may only be reproduced in full.
 This certificate is not transferable and remains the property of the issuing IECQ CB.
 The Status and authenticity of this certificate may be verified by visiting www.iecq.org



Schedule of Scope to Certificate of Approval Independent Testing Laboratory

IECQ Certificate No.: IECQ-L DEKRA 17.0001-01

CB Certificate No.: DEKRA-C10B

Schedule Number: IECQ-L DEKRA 17.0001-01-S Rev No.: 1 Revision Date: 2017/11/27 Page 1 of 1

1. Environmental and Reliability Testing of Electronic Components, Assemblies, and Related Materials

Description test	Standard	Remarks
Accelerated environment reliability stress tests (Including: Pre-condition test/ MSL test/ Accelerated Temperature-Humidity test / Temperature-Humidity with bias test / Temperature Cycling test / Power and temperature cycling / Temperature storage test / Salt)	JESD 47 J-STD-020 JESD22-series IEC-60068-series MIL-STD-202/750/810/883 JESDJP001 EIA-364-32C EIAJED-4701 AEC-Q100 AEC-Q101 AEC-Q200	Or customer specified test

This schedule is only valid in conjunction with the referenced Certificate of Approval
This approval and any schedule(s) may only be reproduced in full.
This approval is not transferable and remains the property of the issuing body.
The Status and authenticity of this approval and any schedule(s) may be verified by visiting the
Official IECQ Website: www.iecq.org

DEKRA Certification B.V. Meander 1051, Arnhem. Netherlands

